



N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 20 V
- Drain-Source On-Resistance
 - $R_{DS(ON)}$ 17m Ω , at $V_{GS}= 4.5V$, $I_{DS}= 6.4A$
 - $R_{DS(ON)}$ 20m Ω , at $V_{GS}= 2.5V$, $I_{DS}= 5.5A$
 - $R_{DS(ON)}$ 25m Ω , at $V_{GS}= 1.8V$, $I_{DS}= 5.0A$
- Continuous Drain Current at $T_A=25^\circ C$ $I_D = 6.4A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free
- ESD protection

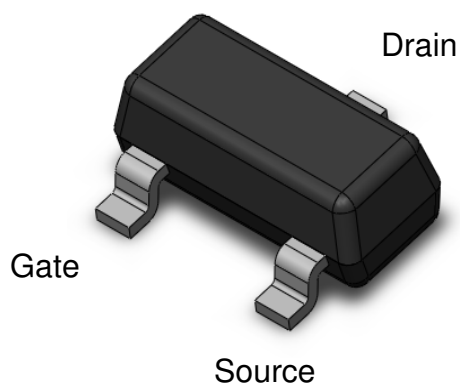
Applications

- Power Management
- Battery Powered System
- Portable Equipment
- DC/DC Converter

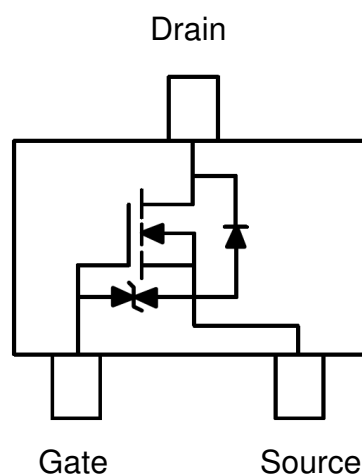
Description

The CTL0642NS-R3 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

Package Outline



Schematic



**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	20	V	
V_{GS}	Gate-Source Voltage	±8	V	
I_D	Continuous Drain Current @ $T_A=25^\circ\text{C}$	6.4	A	1
I_{DM}	Pulsed Drain Current	30	A	1
P_D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	1.4	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\theta JA}$	Thermal Resistance Junction-Ambient (t=10s)		-	75	-	°C /W	1,4

**Electrical Characteristics** $T_A = 25^\circ\text{C}$ (unless otherwise specified)**Static Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	20	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=20V, V_{GS}=0V$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 8V, V_{DS}=0V$	-	-	± 10	μA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=10V, I_D=6.4A$	-	17	21	m Ω	3
		$V_{GS}=10V, I_D=5.5A$	-	20	25	m Ω	
		$V_{GS}=4.5V, I_D=5.0A$	-	25	33	m Ω	
$V_{GS(TH)}$	Gate-Source Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	0.4	0.6	1.0	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{DS}=10V,$ $V_{GS}=0V,$ $f=1MHz$	-	150	-	pF	
C_{OSS}	Output Capacitance		-	95	-		
C_{RSS}	Reverse Transfer Capacitance		-	25	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS}=10V, V_{GS}=5V,$ $R_G=3\Omega, R_L=1.5\Omega$	-	250	300	ns	
T_R	Rise Time		-	420	500		
$T_{D(OFF)}$	Turn-Off Delay Time		-	3950	4200		
T_F	Fall Time		-	3700	3900		
Q_G	Total Gate Charge	$V_{DS}=10V, V_{GS}=4.5V,$ $I_D=6.5A$	-	10	12	nC	
Q_{GS}	Gate-Source Charge		-	0.9	-		
Q_{GD}	Gate-Drain (Miller) Charge		-	3	-		

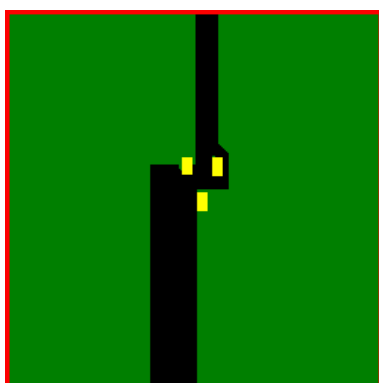


Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = 1A		0.6	1	V	
I _{SD}	Body Diode Continuous Current				1	A	1

Note:

- 1. The power dissipation is limited by 150°C junction temperature.
- 2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

- 3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

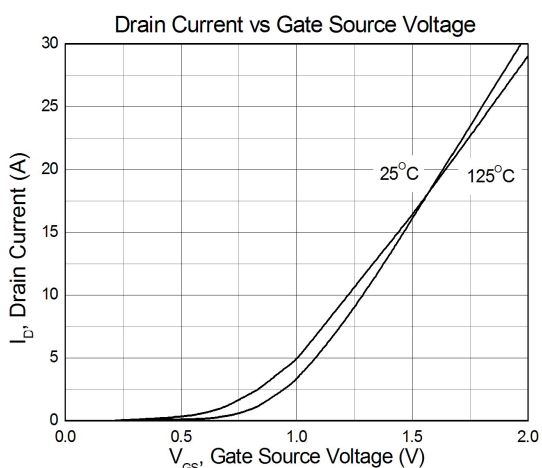


Figure 1

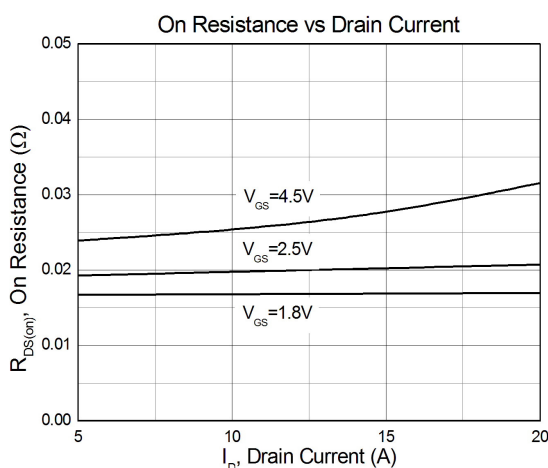


Figure 2

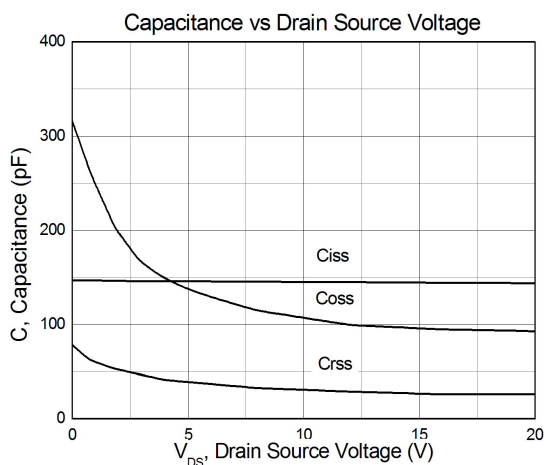


Figure 3

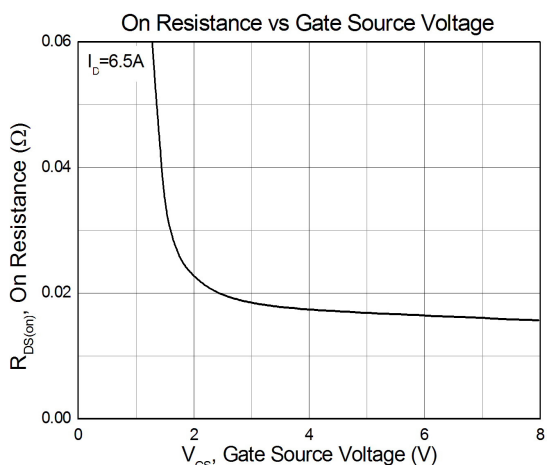


Figure 4

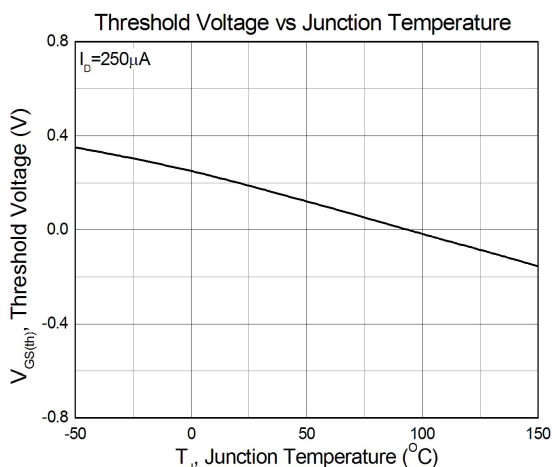


Figure 5

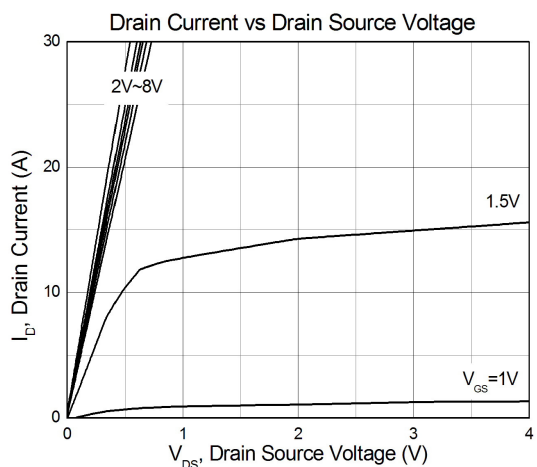
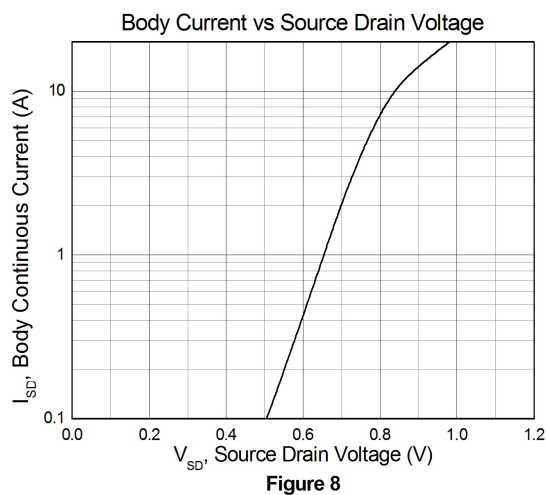
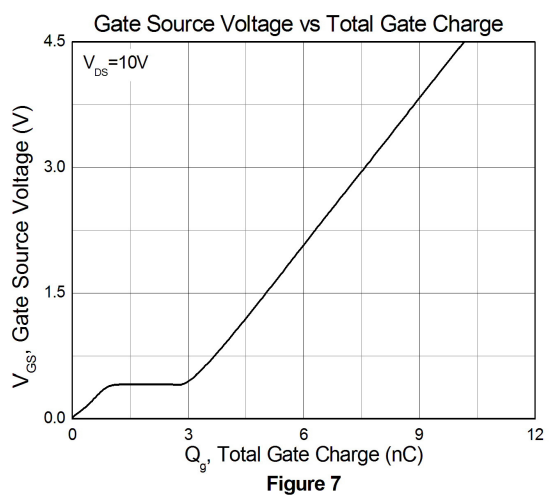


Figure 6





Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

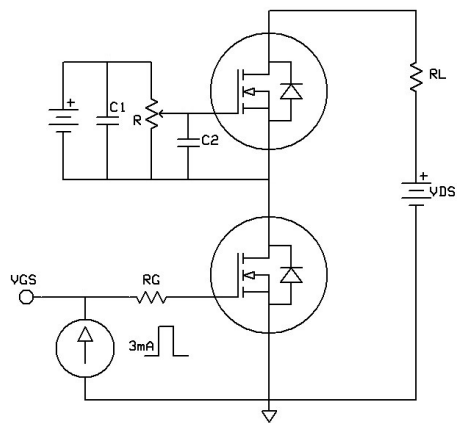


Figure 10: Gate Charge Waveform

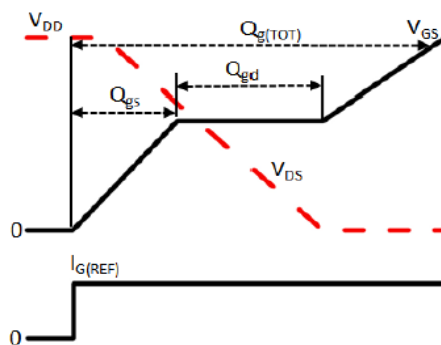


Figure 11: Switching Time Test Circuit

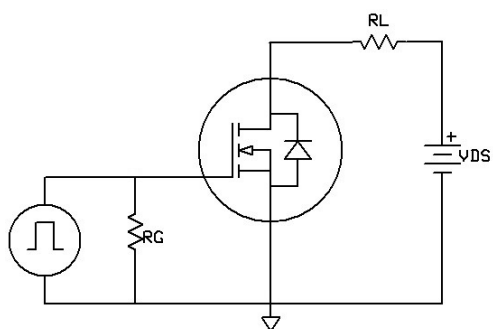
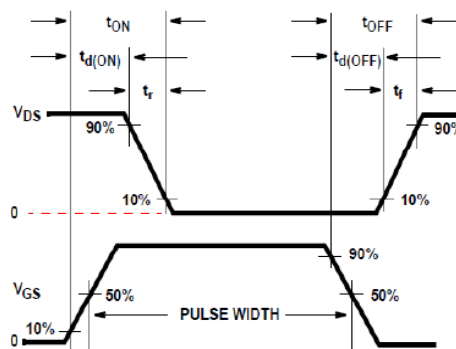
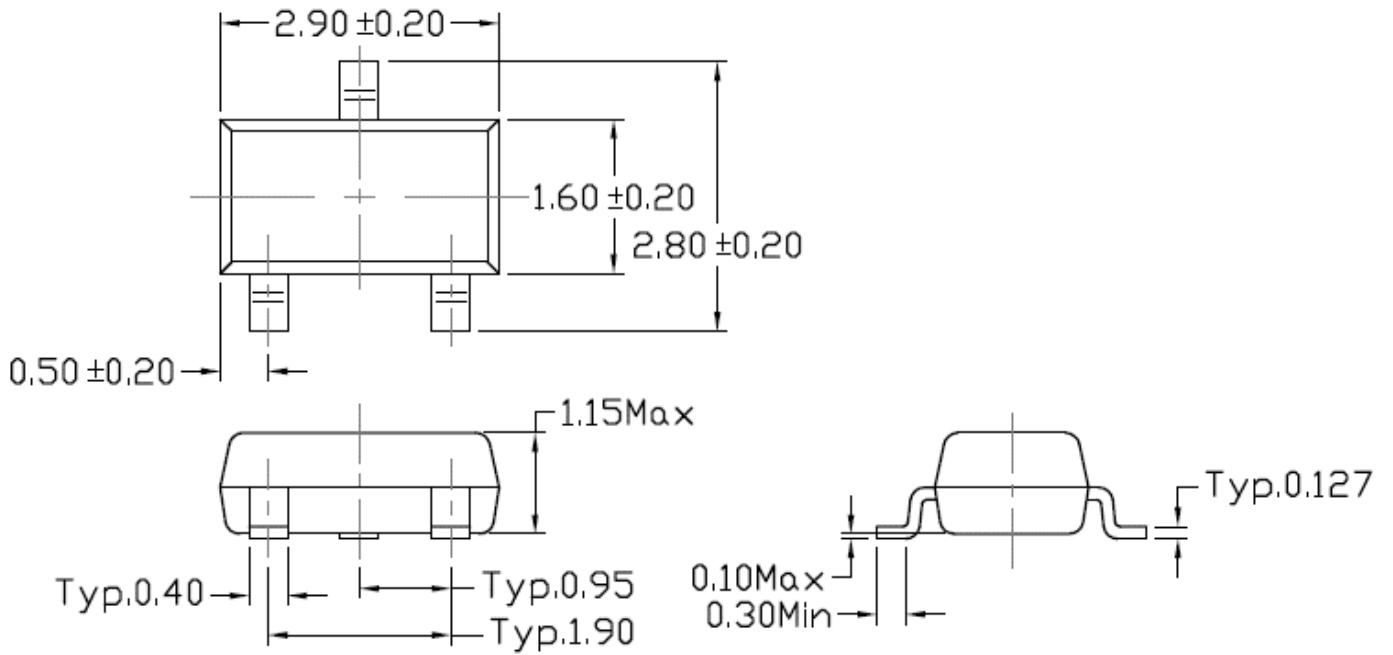


Figure 12: Switching Time Waveform

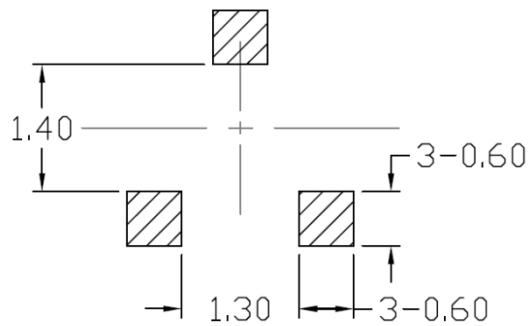




Package Dimension (SC-59)



Recommended pad layout for surface mount leadform

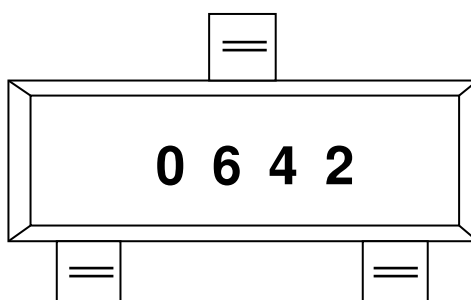




CTL0642NS-R3

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Marking Information



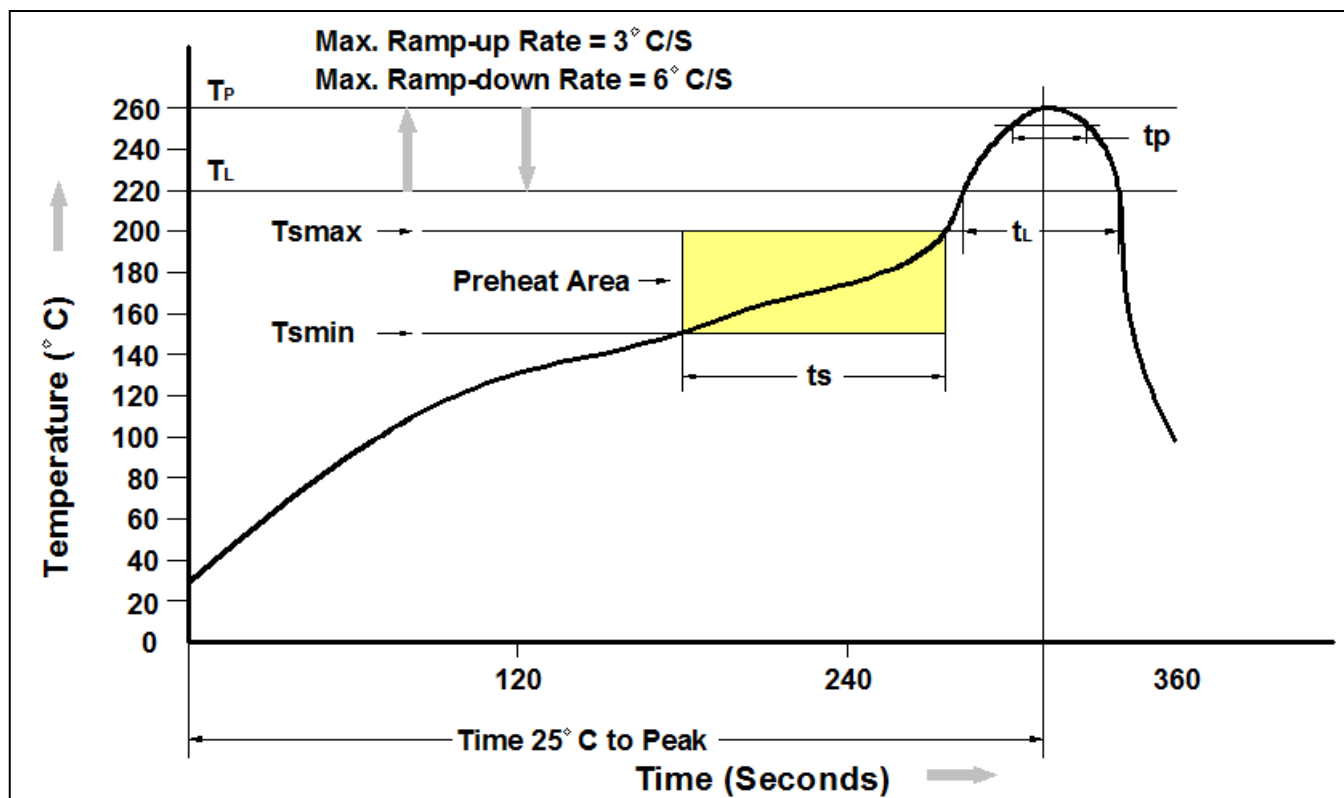
0642 : Device Number

Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CTL0642NS-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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